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# Scoring Bayesian Neural Networks for learning from inconsistent labels in surface defect segmentation

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# ABSTRACT

This paper focus on surface defect segmentation uncertainty challenges that arise due to human errors and biases in the data annotation process, particularly in ambiguous transition and weak feature areas. Firstly, uncertain areas are defined, where it could not be unambiguously identified as defect or defect-free. Then a scoring Bayesian neural network is proposed, using Bayesian neural computation to solve the segmentation probability and provide an expression for uncertain areas. The variance of segmentation probability is utilized to assess the quality of labels, thereby improving model performance. The approach is validated against prevailing state-of-the-art methods on five datasets, demonstrating superior performance. This study provides a crucial pathway for addressing human errors and biases in defect detection. The code is available at https://github.com/ntongzhi/Scoring-BNNs.

### 1. Introduction

Surface defect detection is a crucial component of the manufacturing process, with widespread applications across numerous industries, including workpiece [1], flat steel [2], additive manufacturing [3], and 3C glass [4], among others. In recent years, Convolutional Neural Networks (CNNs) have demonstrated remarkable advancements in the field of surface defect detection, significantly improving performance standards and establishing new benchmarks.

While deep learning models hold considerable potential, these datadriven approaches have been found to reproduce, and in certain instances, even amplify human errors and biases that are intrinsic to the training dataset, particularly those introduced during the labeling process [5,6]. This issue is pervasive, affecting not only natural and medical imagery [7,8], but is notably severe in the sphere of surface defect detection.

The task of annotation of surface defect segmentation confronts two primary challenges: (1) transition areas: in defect detection images, considering the causes of defects like scratches or pollution, there is inevitably an extensive transition area between the normal background and the anomalous foreground; (2) weak features areas: the issue of inter-class similarity is prevalent in defect detection, making it challenging to distinguish the background from the foreground. Moreover, given the irregular contours of defects and the possibility of some being minute enough to evade detection during the labeling process, these weak features areas are particularly prone to being overlooked in the labeling stage.

To compound this, the annotation of transition and weak features areas are subject to a host of variables such as the fluctuating emotional states of workers, differing judgment standards, and varied technical skill levels, thereby causing inconsistent labeling outcomes. As illustrated in Fig. 1, the boundaries of certain areas are marked within a limited range, others within an extensive range, while some areas are disregarded altogether.

A variety of strategies have been proposed to learn from inconsistent labels, incorporating methods based on Bayesian probabilities [9], proxy labels [10], and 'divide-and-rule' approaches [7]. However, these methods predominantly depend on multi-labels, which can prove to be costly for defect detection. Furthermore, our focus should shift towards labels at the pixel-level, as opposed to those at the image level.

In the realm of pixel-level labels, both SEAL [11] and STEAL [12] enhance the delineation of semantic regions by explicitly accounting for annotation inconsistencies during training, thereby leveraging prior knowledge. SEAL reimagines the optimization of latent edge labels as a problem of minimum-cost assignment in a bipartite graph, subsequently adjusting labels during training guided by a biased Gaussian kernel and a Markov prior. On the other hand, STEAL introduces a novel layer and loss function that mandate the edge detector to predict a peak

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Fig. 1. The inconsistent labels. Inconsistent labels are given by general annotators, while highly experienced engineers provide the ground truth. Both are forms of human annotation but vary in expertise and accuracy.

response along the normal direction of the edge, while concurrently regularizing its direction. However, all these approaches operate under the presumption of the existence of precise edges. In industrial inspections, owing to the origins of defects, transitional and weak features areas are widespread. Therefore, the assumption of precise edges often proves fallacious. Even some areas with weak features lack annotations. Thus, simply focusing on label edges is not adequate.

The challenges posed by manual labeling are virtually unavoidable due to the inevitable inconsistencies arising from the annotation process. However, if these challenges are appropriately addressed, they can often aid in resolving practical issues. In this paper, we argue that areas characterized by transition and weak features cannot be unambiguously identified as defect or defect-free, which means that these areas are still uncertain. These uncertain areas embody all pixels that cannot be definitively classified using existing features.

Nonetheless, traditional deep learning models designed for segmentation fail to account for this inherent uncertainty [13]. While Bayesian probability theory provides a mathematical tool to address uncertainty areas, it typically imposes prohibitive computational costs. Consequently, without modifying the model or its optimization, we leverage Monte-Carlo dropout [14] as an approximation of Bayesian inference over the network's weights. This approach allows us to approximate the posterior distribution by drawing samples from the Bernoulli distribution. We weigh and aggregate the results of multiple samplings to generate a segmentation probability map. In this map, areas with a probability of 0 are designated as normal, areas with a probability of 1 as abnormal, and areas with a probability within (0, 1) as uncertain areas.

The chief aim of this paper is to achieve defect detection without the requirement for supplementary data and additional labels. Considering the high costs related to image acquisition and annotation, labels of mediocre consistency and even those tainted by noise should be fully leveraged. Lower label quality equates to higher uncertainty in Bayesian inference, which manifests as heightened variance. Therefore, we propose Scoring Networks (SN) to assess label quality, using the variance from multiple solutions of the Bayesian Neural Networks (BNNs) as the labels for the SN.

In summary, the principal contributions of this paper can be delineated as follows:

(1) We introduce an innovative uncertainty-centric framework that generates segmentation probabilities, thereby providing a representation of uncertainty areas driven by inconsistent labeling.

(2) To fully exploit limited data and labels, we developed the Score-BNN, which utilize the variance from multiple Bayesian Neural Network solutions as an indicator of label quality, thereby enhancing model performance.

(3) Our method was rigorously tested on five publicly accessible datasets, exhibiting comparable or superior performance against established state-of-the-art models, thereby confirming its effectiveness and efficiency.

# 2. Related works

In this paper, Scoring Bayesian Neural Networks are introduced as a novel approach for learning from inconsistent labels in surface defect segmentation. Initially, the fundamental principles and construction methodologies of Bayesian Neural Networks are revisited. This is followed by an organized review of current directions in defect detection research and an overview of the prevalent methods in the field.

#### 2.1. Bayesian Neural Networks

In the realm of deep learning, BNNs [15] offer a probabilistic interpretation of deep learning models by inferring distributions over the models' weights, typically aligning with Gaussian processes. However, the abundance of parameters in these networks complicates the task of modeling a distribution over the kernels, resulting in increased computational demands.

Yarin [13] intriguingly established that employing dropout during the training phase of neural networks can be interpreted as a Bayesian approximation. This insight allows for the avoidance of increased computational complexity or reduced test accuracy. In conjunction with this, Yarin introduced a functional architecture for dropout CNNs [14]. In light of this, the training process of such networks is reinterpreted as an approximate Bernoulli variational inference in BNNs. The evaluation of these models is facilitated by approximating the predictive posterior, a technique referred to as Monte Carlo dropout during the testing phase. Supporting this probabilistic paradigm in deep learning, Alex unveiled the Bayesian SegNet framework [16]. This innovative structure enables probabilistic pixel-wise semantic segmentation, extending beyond the capacities of conventional deep learning models.

Inspired by the aforementioned principles, DropBlock [17] is utilized to construct a Spatial Correlated Bayesian CNN Block, approximating the Bernoulli distribution. This construct is embedded within the U-Net [18] architecture to establish Scoring BNNs. During the testing phase, segmentation probabilities are derived through Monte Carlo dropout.



Fig. 2. The architecture of our proposed Scoring Bayesian Neural Networks for Surface Defects Segmentation.

#### 2.2. Background of surface defect detection

Surface defect detection plays a crucial role in maintaining product quality and process control across diverse manufacturing industries, including automotive parts production and semiconductor fabrication, among others. Given its significance, deep learning-based methods have become a focal point of extensive research [1–4].

Yet, these methods are not without their challenges. A significant impediment is the requirement for extensive labeled datasets, which are often cumbersome and expensive to compile in the field of surface defect detection. This has catalyzed a wave of research centered around data augmentation [19], anomaly detection [20], and domain generalization [21,22].

Techniques like Generative Adversarial Networks (GANs), Variational Autoencoders (VAEs), and Diffusion Models are employed in data augmentation to extrapolate a broader, richer data distribution from limited datasets. These methods enhance data diversity, amplifying the model's grasp of potential data representations. Anomaly detection strategies capitalize on the ease of gathering positive (nondefective) samples to create a distribution model of positive sample features using reconstructive or feature embedding models, making defect identification more straightforward. In essence, by delineating the 'normal' data representation, anomalies or defects are rendered more detectable. Domain adaptation techniques, on the other hand, offer a solution to the adaptation challenges posed by varying types, batches, and data distributions, without the need for exhaustive data collection or labeling for every new task.

Although the issues pertaining to the data itself have been extensively studied, there has been limited research on labels. In this paper, the focus is placed on inconsistent labels resulting from human errors and biases. The causes behind these inconsistent labels are meticulously analyzed. Based on these insights, an uncertainty-centric framework is proposed, which generates segmentation probabilities by harnessing uncertainty quantification to enhance the reliability and robustness of surface defect detection.

#### 3. Proposed approach

# 3.1. Overview

The architecture of the proposed Scoring Bayesian Neural Networks for Surface Defect Detection (Score-BNN) is characterized by two distinct phases: training and testing, as illustrated in Fig. 2.

In the training phase, we feed the input to the Bayesian Neural Network (BNN) N times to generate N unique segmentation results (Seg). These results are subsequently compared with the label to derive the segmentation errors (Seg error). Concurrently, we employ the Scoring Networks (SN) to evaluate the label's score (Score), which requires the concatenation of the input and label as its input. The scoring loss ( $Loss_{score}$ ) is calculated as the variance of the Seg error (Var) minus the Score, and is utilized to back-propagate the SN. The segmentation loss ( $Loss_{seg}$ ) is computed as the product of the Score and the mean of the Seg error (Mean), and serves to back-propagate both the SN and BNN.

In the testing phase, the BNN is run N times with the same input, yielding multiple distinct segmentation results (Seg). The SN is then utilized to compute the Seg score from the concatenation of Seg and the input. Each Seg is subsequently weighted by its corresponding Seg score, and the results are aggregated to yield the final segmentation probability.

### 3.2. Bayesian Neural Networks for surface defects detection

# 3.2.1. Probabilistic modeling

Given the training inputs  $\{x_1, ..., x_N\}$  and corresponding labels  $\{y_1, ..., y_N\}$ , our goal is to estimate a function y = f(x). In the Bayesian approach, we impose a prior distribution over the function space, denoted as p(f). Subsequently, we seek the posterior distribution over the same space conditioned on our dataset, i.e.,  $p(f \mid X, Y)$ .

In the context of Bayesian neural networks, our primary interest lies in discovering the posterior distribution over the convolutional weights.

$$w = (W_i)_{i=1}^I \tag{1}$$



Fig. 3. Spatially correlated Bayesian CNN block. (a) is the original CNN block, (b) is the spatially correlated Bayesian CNN block.

where  $W_i$  represents the weights of the *i*th layer in the convolutional network. However, the distribution  $p(w \mid X, Y)$  is not analytically tractable. Consequently, we define an approximation variational distribution q(w) to approximate p(w). Inspired by [14], we employ Gaussian prior distributions to approximate q(w). Subsequently, the Gaussian process can be approximated using Bernoulli-distributed random variables with dropout probabilities  $b_{i,j}$  and variational parameters of the CNN's kernels,  $K_i$ . Here,  $b_{i,j}$  is the dropout probability of the *j*th neuron in the *i*th layer of the network, while  $K_i$  is the convolutional kernel of the *i*th layer of the network. Consequently,  $q(W_i)$  is defined for every layer *i* as follows:

$$W_{i} = K_{i} \cdot diag([b_{i,j}]_{j=1}^{J})$$
  

$$b_{i,i} \sim Bernoulli(p_{i}) f \text{ or } i = 1, \dots, I, j = 1, \dots, J$$
(2)

The operator  $diag(\cdot)$  transforms vectors into diagonal matrices whose elements originate from the vector.  $p_i$  signifies a fixed Bernoulli distribution probability, generally set at  $p_i = 0.5$ . The network comprises *I* layers in total, each containing *J* neurons.

In networks inference, we approximate the integral with Monte Carlo integrations:

$$p(y^*|x^*, X, Y) \approx \frac{1}{T} \sum_{t=1}^T \hat{f}(x^*, \hat{w}_t)$$
(3)

where  $x^*$  and  $y^*$  are the input and output in test set, and  $\hat{w}_t \sim q(w)$ . *T* is a hyperparameter used to balance the accuracy of calculation results and computational overhead.

# 3.3. Spatially correlated Bayesian CNN block

Dropout is implemented following convolution layers in numerous approaches to create Bayesian neural networks [13,16,23]. However, due to the spatial correlation of convolutional layers, the efficacy of dropout tends to diminish. Motivated by DropBlock [17], we propose a spatially correlated Bayesian CNN block.

Initially, batch normalization is substituted with dropout in the CNN block. A standard CNN block is composed of a convolution, batch normalization, and an activation function. According to Eq. (2), dropout should be applied post-convolution to enable the formation of a Bayesian CNN block. However, merging the potent techniques of Dropout and Batch Normalization can, at times, lead to a decrement in



Fig. 4. Activation map of varying dropout results in the NEU-Seg dataset.

performance [24]. Consequently, batch normalization is replaced with dropout, giving rise to the basic architecture of the Bayesian CNN block. This revised structure encompasses a convolution, followed by dropout, and culminating with an activation function, as illustrated in Fig. 3.

Following that, the influence of diverse dropout structures on CNN is examined. Standard dropout operates by selectively disabling specific features. However, when these features are correlated, the exclusion via dropout does not wholly eliminate the input information, resulting in a prior loss of variance. This paper introduces DropBlock that operates by disabling entire blocks of pixels, as illustrated in Fig. 4. An activation map is utilized to visualize the activations of the convolutional layer before the initial up-sampling in the BNN. Typically, models that are trained using a spatially correlated Bayesian CNN block are adept at learning spatially distributed representations, leading to heightened activations in precise regions. In contrast, models lacking adequate regularization are prone to concentrating on broader, less accurate regions.

# 3.4. Networks design

The overall structure of our network, as demonstrated in Fig. 2, is designed based on U-Net [18]. This model performs optimally on the majority of defect detection datasets, as evidenced in Table 3 4 5 6 7. This performance can potentially be attributed to the relatively fixed structure of industrial images and the simplicity of their semantics, wherein low-level features hold comparable importance to high-level ones.

In practice, excessive regularization may inhibit the speed of network learning. With partial Bayesian CNN blocks, however, we can realize a Bayesian CNN. Thus, we explore the optimal quantity and placement for the Bayesian CNN block. As shown in Table 2, Intersection over Union (IoU) and Pixel Accuracy (PA) are maximized when the Bayesian CNN block is positioned in the last two layers of the encoder and in the central layer. These findings indicate that applying the Bayesian CNN block to the lower layers does not yield superior performance. Low-level features such as edges and corners are consistent across the distribution of models, whereas high-level features like shape and context are more effectively modeled with the Bayesian CNN block. Furthermore, the decoder maps the latent representation to a semantic segmentation result, taking into account both high-level and low-level information.

# 3.5. Scoring networks

# 3.5.1. Motivation

In the training phase, we employ SN where labels of higher quality are assigned higher scores. Through a weighted contribution mechanism, these high-quality labels play a more substantial role in training the model, leading to enhanced robustness. During the testing phase, the challenge of inconsistency extends to the segmentation results derived from BNNs. A simplistic averaging method in this scenario would exacerbate uncertainty. Counteracting this, the SN network appraises and assigns weights to the segmentation outputs, prioritizing those of higher quality and fostering the extraction of higher quality segmentation probabilities.

### 3.5.2. Methodology

During the training process, different levels of inconsistency among annotations may exhibit varying rates of loss descent. Upon training completion, the predicted segmentations for the inconsistent labels could present a higher uncertainty loss in comparison with wellannotated ones. In this context, we postulate that a larger variance in segmentation error corresponds to greater label inconsistency.

As depicted in Fig. 2, during the training phase, the mean of segmentation errors is reweighted by the Scores, computed by the Scoring Network (SN) using the concatenation of inputs and labels. The Bayesian Neural Network (BNN) then backpropagates based on the reweighted loss  $Loss_{seg}$ , prioritizing those with higher uncertainty, while the SN backpropagates based on both  $Loss_{score}$  (the difference between the Score and the variance of segmentation errors) and  $Loss_{seg}$ .

The design of the SN is based on the encoder of the BNN, excluding the Bayesian NN block. In the final layers, we incorporate a global average pooling operation to obtain the score for each input in a minibatch. To circumvent potential overfitting, which could result in an excessively large or small score, we introduce the activation function tanh after the final layer, constraining the score within the range of [-1,1]. Following processing by the softmax layer, the maximum possible ratio of two scores within the same mini-batch is confined to the range  $[e^2, \infty]$ .

#### 3.6. Training mechanism

Let us denote the training set samples as  $\{x_1, \ldots, x_N\}$ , with their corresponding annotations represented by  $\{y_1, \ldots, y_N\}$ . The segmentations of the *i*th sample in the training set, computed *M* times by the Bayesian Neural Network (BNN), are designated as  $\{\hat{y}_1, \ldots, \hat{y}_M\}$ . Additionally, the scores of the annotations, calculated by the Scoring Network (SN), are represented by  $\{s_1, \ldots, s_N\}$ .

In the realm of defect detection, the background area typically greatly surpasses the defect area in size. As a remedy to this imbalance, we utilize a combination of Binary Cross Entropy (BCE) loss and Dice coefficient (Dice) loss functions:

$$BceLoss_{i}^{j} = -y_{i} \cdot log\left(\hat{y}_{i}^{j}\right) - (1 - y_{i}) \cdot log\left(1 - \hat{y}_{i}^{j}\right)$$

$$(4)$$

$$DiceLoss_{i}^{j} = 1 - 2 \cdot \left| V_{y_{i}} \bigcap V_{\hat{y}_{i}^{j}} \right| / \left( \left| V_{y_{i}} \right| + \left| V_{\hat{y}_{i}^{j}} \right| \right)$$
(5)

$$Loss_{i}^{j} = \lambda BceLoss_{i}^{j} + DiceLoss_{i}^{j}$$
(6)

In the aforementioned equation, V represents the segmented area of the samples, while  $\lambda > 0$  acts as a hyperparameter balancing the relative significance of the two components, namely the BCE and Dice losses.

Subsequently, the mean and variance of the loss (*Loss*) are computed as follows:

$$Mean_i = \frac{1}{M} \sum_{j=1}^{M} Loss_i^j \tag{7}$$

$$Var_{i} = \frac{1}{M} \sum_{i=1}^{M} \left( Loss_{i}^{j} - Mean_{i} \right)$$
(8)

Hence, the loss associated with segmentation is computed as:

$$Loss_{seg} = \sum_{i=1}^{N} s_i \cdot Mean_i \tag{9}$$

Extending this, we establish the label for the score as follows:

$$ls_i = softmax\left(-\frac{e^{-\hat{\lambda}\cdot Var_i}}{1+e^{-\hat{\lambda}\cdot Var_i}}\right), i = 1, \dots, N$$
(10)

where  $\hat{\lambda}$  serves as a hyperparameter designed to adjust for variance. Finally, the score loss is defined as:

$$Loss_{score} = \frac{1}{N} \sum_{i=1}^{N} -ls_i \cdot log(s_i) - (1 - ls_i) \cdot log(1 - s_i)$$
(11)

# 3.7. Sematic segmentation probability

Finally, we approximate the semantic segmentation probability utilizing Monte Carlo integrations. As illustrated in Fig. 2, a sample from the testing set is denoted by  $x^*$ .  $\{y_i^*, \ldots, y_k^*\}$  represents the segmentation of  $x^*$  calculated K times by the BNN, while  $s_k^*$  is computed by the SN via the concatenation of  $y_k^*$  and  $x^*$ . Following Eq. (3), the probability is determined as:

$$p(x^*) \approx \sum_{k=1}^{K} s_k^* \cdot y_k^*$$
(12)

# 4. Experiments and results

# 4.1. Implementation details

#### 4.1.1. Parameters setting

The model is based on VGG Block, with each VGG Block consisting of two  $3 \times 3$  convolutions. After each convolution operation, batch normalization is used for regularization, and the ReLU activation function is employed to introduce non-linearity. Downsampling is achieved using  $2 \times 2$  max pooling, while upsampling employs  $2 \times$  bilinear interpolation. The BNN network undergoes 4 downsampling and 4 upsampling processes. The SN network also goes through 4 downsampling processes. The mini-batch size is consistently set at 4. In the BNN, the initial learning rate is established at 0.003 and is designed to decrease at a rate of 0.0001. Conversely, the SN operates with a learning rate of 0.00001. Furthermore, the Dropout probability is set at 50%.

#### 4.1.2. Computation platform

Our implementation of Score-BNN is constructed in the PyCharm environment, leveraging the open-source Pytorch toolkit. The model's training is carried out on a high-performance server, outfitted with an NVIDIA Tesla A100 GPU (boasting 40 GB memory) and operating on a CentOS 8 Linux system. Moreover, to ensure the practical applicability of our method in industrial settings, we assessed its performance on an economical, low-computational-power PC setup equipped with a GTX 1070 GPU, boasting 8 GB of memory.

#### 4.2. Dataset

In this study, we have selected five datasets to examine the applicability and generalizability of our proposed method. These datasets encompass three benchmarks: NEU-Seg [25], MTDD [26] defect dataset, and KSDD [27] defect dataset. Additionally, we included two datasets derived from real industrial production lines: MCSD-Seg [20], which focuses on motor commutators, and WDD, which is dedicated to wafers.

#### 4.3. Evaluation metrics

To assess the segmentation capability, we employ intersection-overunion (IoU) and pixel-accuracy (PA) as performance metrics, using them to compare with other segmentation methods. To manifest the network's capacity for modeling uncertainty, we utilize a lower approximation for accuracy computation and an upper approximation for recall rate calculation. Ultimately, we adopt F1-Score, a measure that combines both accuracy and recall rate.



Fig. 5. The convergence performance of BNNs and SN.

Table 1	
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Performance results of various module on the NEU-Seg Dataset.

	CNN	Bayesian CNN block	Score net	IoU	PA
s1				0.7590	0.9676
s2	V	$\checkmark$		0.7693	0.9693
s3	V		$\checkmark$	0.7570	0.9670
s4				0.7771	0.9696

## 4.4. Convergence performance

In this section, we evaluate the convergence performance of BNNs and SN utilizing the NEU-Seg dataset. We plot the loss value trajectory over the training epochs to visualize the model's convergence pattern, as shown in Fig. 5.

The BNNs loss curve showcases a systematic decline, marked by a consistent and smooth trajectory, punctuated by a gradually decelerating rate of decrease. This behavior is indicative of an efficient convergence performance, aligning seamlessly with the expected pattern associated with a reducing learning rate.

Conversely, the SN convergence trajectory, though characterized by noticeable fluctuations, underscores an overarching downward trend, attesting to its effective convergence. The slight decrease in the SN curve is associated with its fitting task and is reasonable, given its learning rate is set at a mere 0.000001 — three orders of magnitude lower than the BNN's learning rate of 0.003.

An initial upward spike in the SN curve is observable, a phenomenon we attribute to the restrictive labels generated from the variance of the BNNs during the early training stages. This ascent is inherently linked to the BNNs' initial performance constraints. However, a transition occurs as the BNNs' performance plateaus; correspondingly, the SN curve embarks on a consistent downward trajectory, underscoring a harmonious interplay between the convergences of the two models.

# 4.5. Ablative study

# 4.5.1. An ablation study of various modules

In order to validate the effectiveness of each module in our proposed method, we conduct a series of ablation studies. Initially, we utilize CNN networks devoid of the Bayesian CNN block and SN as a control group. Following this, we deploy the combination of CNN and SN to ascertain the efficacy of the SN. The combination of CNN and Bayesian CNN block is utilized to verify the potency of the Bayesian

Table 2			
Performance result	s of diverse architectural	l variants on the NEU-Seg	Dataset.

		IoU	PA
s1	No Dropout	0.7570	0.9670
s2	Dropout Encoder	0.7559	0.9674
s3	Dropout Decoder	0.5373	0.9343
s4	Dropout Center	0.7617	0.9676
s5	Dropout Classifier	0.6538	0.9511
s6	Dropout Central Enc-Dec	0.7733	0.9691
s7	Dropout Central Enc	0.7771	0.9696

CNN block. Finally, the amalgamation of all three elements constitutes our network.

As demonstrated in Table 1, the IoU of the Bayesian CNN block improves by 1.03% in comparison to the control group, and our proposed method further enhances it by 0.78% on this basis. Conversely, it can be observed that the standalone SN incurs almost no improvement. Based on our analysis, the SN operates in concert with the Bayesian neural network, functioning under the precondition of variance in multiple solutions.

# 4.5.2. Various architectural variants

In an effort to substantiate the assertions made in Section 3.4, we assessed the performance of the Bayesian CNN Block in various positions while maintaining constant network structure and dataset. As shown in Tabel 2, scenarios included no Dropout (s1), presence of Dropout only in the Encoder section (s2), Decoder section (s3), center section (s4), final classification operation (s5), center and the two layers of Encoder and Decoder near the center (s6), and finally, center and two layers of Encoder proximal to the center (s7).

The results revealed a detrimental effect of Dropout on the Decoder part and classification operation. However, positive influences were evident in the Encoder and center sections, with the latter demonstrating a stronger effect. This corroborates our stance that the Bayesian operation exhibits superior performance in the high-level feature layer. Ultimately, the most optimal effect was observed when the Bayesian operation was applied at the center layer and the Encoder layer adjacent to the center, achieving an IoU of 77.71%.

#### 4.6. Comparison results with state-of-the-art methods on five datasets

Initially, we juxtapose our method with Bayes-SegNet [16] (2015), a semantic segmentation model premised on Bayesian neural networks. Following that, we compare our methodology with conventional



Fig. 6. Visualization results on the NEU-Seg dataset.

Table 4

Methods

U-Net (2015)

SegNet (2017)

PSPNet (2017)

CCNet (2019)

RefineNet (2017)

DeepLaby3+ (2017) PGANet (2019)

TopFormer (2022)

Swin UNet (2023)

Bayes-SegNet (2015)

LSA-Net (2023)

FCN (2015)

Table 3

Comparison results on NEU-Seg datasets.

Methods	IoU	PA	F1
U-Net (2015)	0.7590	0.9696	0.8659
SegNet (2017)	0.7241	0.9613	0.8421
FCN (2015)	0.7372	0.9646	0.8490
PSPNet (2017)	0.6453	0.9524	0.7799
RefineNet (2017)	0.5600	0.9124	0.7355
DeepLabv3+ (2017)	0.7350	0.9643	0.8906
PGANet (2019)	0.7517	0.9668	0.8620
CCNet (2019)	0.6292	0.9503	0.7557
TopFormer (2022)	0.7315	0.9625	0.8363
Swin UNet (2023)	0.7005	0.9578	0.8151
LSA-Net (2023)	0.7595	0.9665	0.8568
Bayes-SegNet (2015)	0.7477	0.9650	0.9168
Ours	0.7771	0.9696	0.9329

semantic segmentation models, including U-Net (2015) [18], Seg-Net (2017) [28], FCN (2015) [29], PSPNet (2017) [30], RefineNet (2017) [31], Deeplab (2017) [32], PGANet (2019) [33], CCNet (2019) [34], TopFormer (2022) [35], Swin UNet (2023) [36], and LSA-Net (2023) [37]. For a clearer visual comparison, the final semantic segmentation results are presented as heat maps.

#### 4.6.1. Results on NEU-Seg dataset

The visual comparison between our approach and other methods for NEU-Seg images is illustrated in Fig. 6. Due to the complexities in hot-rolled conditions, some of the inclusion defects (row 1-2) and the patches defects (row 6-7) exhibit discernible gradual regions at the boundaries, and the scratches defects (row 3-5) contrast poorly with the background. Consequently, in the inconsistent labels, some defects are not annotated, while some boundaries are inaccurate. Evidently, our method outperforms the others. Score-BNN not only segments out the unlabeled parts of the image but also illustrates the transitional regions probabilistically. As demonstrated by the quantitative comparisons in Table 3, our approach exceeds existing methods in all three metrics, improving the IoU value to 77.71%.

#### 4.6.2. Results on MTDD

As depicted in Fig. 7, due to the variability of defect shapes and the randomness of lighting conditions, defects in the corners (row 1, 3), very small defects (row 2), and suspected defects (row 4) are not annotated. It can be observed that the performance of our method more closely approximates the real scenario. As outlined in Table 4, our method enhances the IoU value to 75.73%.

Ours		
Table 5		

Comparison	results	on	KSDD	d

Comparison results on MTDD datasets

IoU

0.7358

0 6614

0.7144

0.5463

0.0982

0.7286

0.7165

0.5734

0.6648

0.0877

0.7105

0.7211

0.7573

PA

0.9748

0 9739

0.9821

0.9745

0.8832

0.9802

0.9818

0.9786

0.9739

0.8338

0.9694

0.9770

0.9796

F1

0.8548

0.8028

0.8363

0.7002

0.3723

0.8468

0.8182

0.7019

0.7611

0.2459

0.8080

0.9112

0.8965

Comparison results on KSDD datasets.				
Methods	IoU	PA	F1	
U-Net (2015)	0.8970	0.9988	0.9463	
SegNet (2017)	0.8756	0.9985	0.9334	
FCN (2015)	0.8350	0.9980	0.9116	
PSPNet (2017)	0.4946	0.9910	0.6661	
RefineNet (2017)	0.6655	0.9956	0.8024	
DeepLabv3+ (2017)	0.4668	0.9937	0.6531	
PGANet (2019)	0.7859	0.9969	0.8780	
CCNet (2019)	0.4915	0.9908	0.6501	
TopFormer (2022)	0.8040	0.9976	0.8873	
Swin UNet (2023)	0.7873	0.9974	0.8704	
LSA-Net (2023)	0.8999	0.9989	0.9450	
Bayes-SegNet (2015)	0.8818	0.9986	0.9620	
Ours	0.9197	0.9991	0.9621	

#### 4.6.3. Results on KSDD

Fig. 8 displays a visual comparison of partial KSDD defect image detection results. The primary challenge with this dataset lies in the very small size of the defective samples, albeit the annotations are almost consistent. Nevertheless, it can be observed that our results bear a strong resemblance to the labels. Also, certain suspected areas have been marked in rows 3-4. As detailed in Table 5, we have managed to elevate the IoU value to 91.97%.

#### 4.6.4. Results on MCSD-Seg

Fig. 9 showcases a portion of the MCSD-Seg results and the corresponding predictions. As the surface of the motor commutator images







Fig. 8. Visualization results on the KSDD dataset.



Fig. 9. Visualization results on the MCSD-Seg dataset.

Table 6	
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Comparison results on MCSD-Seg datasets.

	0		
Methods	IoU	PA	F1
U-Net (2015)	0.8336	0.9923	0.9058
SegNet (2017)	0.7347	0.9911	0.8512
FCN (2015)	0.8194	0.9918	0.8889
PSPNet (2017)	0.7948	0.9895	0.8807
RefineNet (2017)	0.6179	0.9867	0.7810
DeepLabv3+ (2017)	0.8537	0.9932	0.9141
PGANet (2019)	0.7611	0.9882	0.8471
CCNet (2019)	0.7253	0.9868	0.7968
TopFormer (2022)	0.7992	0.9891	0.8585
Swin UNet (2023)	0.6911	0.9892	0.7556
LSA-Net (2023)	0.8439	0.9930	0.8954
Bayes-SegNet (2015)	0.8361	0.9922	0.9449
Ours	0.8558	0.9931	0.9456

is curved, it leads to uneven illumination, making some defects appear with low contrast against the background, and brightening some areas. It can be discerned that BNN-SDD sensitively detects the suspicious sections of the image, and its contours align more closely with the actual situation. As indicated in Table 6, the IoU value has been elevated to 85.58%, with PA and F1-Score also delivering superior performance.

#### 4.6.5. Results on WDD

Fig. 10 depicts the WDD, wherein the background exhibits dense intersecting lines of varying shapes. These lines mingle with defects, creating noise that hinders inspection. Concurrently, these defects are small in size, possess a diversity of shapes, and some have indistinct features with low contrast. Nevertheless, the WDD is annotated by professional wafer inspection engineers, providing high-quality labels. Hence, this serves as a control group to underscore that our method demonstrates potent semantic segmentation in high-quality datasets. Consequently, as shown in Table 7, the IoU is amplified to 91.09%.

# 4.7. Scalability experiments on scoring Bayesian networks

To validate the effectiveness of the proposed method on other segmentation models, we conducted experiments on several classic networks including SegNet [28], FCN [29], DeepLabV3+[32], PSP-Net [30], and RefineNet [31] on the NEU-seg dataset.

Our findings, detailed in Table 8, indicate a consistent improvement in performance metrics including IoU, PA, and F1 when our Scoring Bayesian segmentation model is applied. This is demonstrative of the method's adaptability and effectiveness across a diverse array of segmentation models, evidencing its scalable nature. Specifically, models like U-Net, SegNet, and DeepLabV3+ witnessed a 1%–2% uptick in IoU. The marginal improvement observed in FCN and PSPNet can likely



Fig. 10. Visualization results on the WDD dataset.

Table 7

Comparison results on WDD datasets.

Methods	IoU	PA	F1
U-Net (2015)	0.8213	0.9999	0.9049
SegNet (2017)	0.8604	0.9999	0.9272
FCN (2015)	0.0698	0.9995	0.1305
PSPNet (2017)	0.2929	0.9993	0.5720
RefineNet (2017)	0.0698	0.9995	0.1305
DeepLabv3+ (2017)	0.7211	0.9999	0.8365
PGANet (2019)	0.6733	0.9999	0.7894
CCNet (2019)	0.3242	0.9991	0.4698
TopFormer (2022)	0.8143	0.9999	0.8877
Swin UNet (2023)	0.7810	0.9999	0.8569
LSA-Net (2023)	0.8475	0.9999	0.9091
Bayes-SegNet (2015)	0.7572	0.9999	0.9084
Ours	0.9109	1.0000	0.9558

#### Table 8

Quantitative comparison in scalability experiments.

Methods	IoU	PA	F1
U-Net (2015)	0.7590	0.9696	0.8659
Scoring Bayesian U-Net (Ours)	0.7771	0.9696	0.9329
SegNet (2017)	0.7241	0.9613	0.8421
Scoring Bayesian SegNet	0.7441	0.9657	0.9090
FCN (2015)	0.7372	0.9646	0.8490
Scoring Bayesian FCN	0.7414	0.9647	0.8965
PSPNet (2017)	0.6453	0.9524	0.7799
Scoring Bayesian PSPNet	0.6460	0.9513	0.8098
RefineNet (2017)	0.5600	0.9124	0.7355
Scoring Bayesian RefineNet	0.7431	0.9651	0.8635
DeepLabv3+ (2017)	0.7350	0.9643	0.8906
Scoring Bayesian DeepLabv3+	0.7498	0.9661	0.8949

be attributed to the intrinsic network structures and how the spatially correlated Bayesian CNN block is integrated within these networks. Further investigations in optimizing this integration could potentially unlock more pronounced improvements. RefineNet, on the other hand, manifested significant enhancement, an outcome we attribute to the ameliorated convergence facilitated by our method, addressing the original model's convergence inadequacies.

Visual insights from Fig. 11 corroborate these quantitative findings. The refined segmentation probability maps for U-Net, SegNet, and DeepLabv3+ obtained via our method exhibit enhanced alignment with actual defect scenarios, attesting to the method's efficacy. The performance increment is relatively subdued for FCN and PSPNet, marked by less precise segmentation in areas of uncertainty. In the context of RefineNet, our Scoring Bayesian approach not only refines the contours in the segmentation results but also offers a more nuanced, restrained, and accurate representation of uncertain areas, mitigating the original method's overemphasis in these regions.

Table 9		
Computational	efficiency	analysis.

Methods	Times (ms)	Model size (MB)
U-Net (2015)	7.47	29.96
SegNet (2017)	9.29	112.32
FCN (2015)	7.62	85.27
PSPNet (2017)	14.21	177.70
RefineNet (2017)	33.14	450.16
DeepLabV3+ (2017)	24.23	226.37
PGANet (2019)	19.07	198.36
CCNet (2019)	47.08	259.47
TopFormer (2022)	20.29	11.43
Swin UNet (2023)	23.50	103.55
LSA-Net (2023)	15.48	92.54
Bayes-SegNet (2015)	11.89	112.32
Ours	14.90	47.93

# 4.8. Computational efficiency study

To our knowledge, the demands of automated optical inspection are stringent, requiring exceptional real-time performance. In light of this, we have assessed the computational efficiency of our model on a conventional personal computer setup. The number of calculations by BNN is set at M = 16. As delineated in Table 9, our model distinguishes itself by being both compact (with a model size of 47.93 MB) and highly computationally efficient, processing images at a rate of 14.90 ms/image. These attributes underscore its significant competitive edge over prevailing methods.

#### 5. Conclusion and future work

In this paper, we have introduced the Scoring Bayesian Neural Networks for Surface Defect Detection (Score-BNN), a novel framework that explicitly addresses the challenge of inconsistent labeling in surface defect detection. Our approach leverages the concept of uncertainty derived from Bayesian Neural Networks to generate probabilistic, pixelwise segmentation, effectively overcoming the biases and errors often embedded within the labeling process.

Our method capitalizes on inconsistencies in the labeling process, viewing them as indicators of inherent uncertainties rather than as mere noise. The proposed Scoring Networks (SN) use variance from multiple solutions of the Bayesian Neural Networks as an innovative measure of label quality, facilitating better utilization of available data and improving overall detection performance. Our extensive experiments on five publicly available datasets validated the superiority of our approach over state-of-the-art methods. The results demonstrated robustness and adaptability to real-world industrial surface defect detection tasks.

In conclusion, this research highlights the potential of embracing uncertainty and label quality considerations in the development of more robust and reliable deep learning models for surface defect detection. The methodologies we have proposed provide significant insights that will contribute to advancements in the field.



Fig. 11. Visualization results of Scalability experiments.

In future work, we intend to investigate the inconsistencies in labeling attributed to imaging-related challenges, notably uneven lighting and defocus blur. These issues are known to induce gradual textural transitions, which in turn manifest as transition areas and weak feature regions in the imagery. Our approach will encompass a hardwarecentric methodology, wherein we aim to capture and analyze images of identical workpieces under varied lighting conditions, including but not limited to low ring light and coaxial light settings. By conducting a comparative analysis of features extracted from these diverse imaging conditions, we anticipate developing robust solutions to effectively address and rectify these labeling inconsistencies.

#### CRediT authorship contribution statement

**Tongzhi Niu:** Conceptualization, Methodology, Validation, Writing – original draft, Writing – review & editing. **Biao Chen:** Methodology, Software, Validation, Visualization. **Qianhang Lyu:** Visualization, Writing – original draft. **Bei Li:** Data curation, Resources, Software, Validation, Visualization. **Wei Luo:** Funding acquisition, Writing – review & editing. **Zhenrong Wang:** Supervision, Writing – original draft, Writing – review & editing. **Bin Li:** Conceptualization, Project administration, Supervision, Writing – review & editing.

#### Declaration of competing interest

The authors declare that they have no known competing financial interests or personal relationships that could have appeared to influence the work reported in this paper.

#### Data availability

Data will be made available on request.

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